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## **ON Semiconductor**®

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November 2015

## **FCP125N60E**

## N-Channel SuperFET<sup>®</sup> II Easy-Drive MOSFET

600 V, 29 A, 125 m $\Omega$ 

#### Features

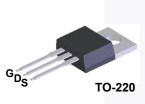
- 650 V @T<sub>J</sub> = 150°C
- Typ. R<sub>DS(on)</sub> = 102 mΩ
- Ultra Low Gate Charge (Typ. Q<sub>g</sub> = 75 nC)
- Low Effective Output Capacitance (Typ. C<sub>oss(eff)</sub> = 258 pF)
- 100% Avalanche Tested
- RoHS Compliant

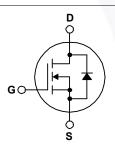
#### Applications

- Telecom / Sever Power Supplies
- Industrial Power Supplies

### Description

SuperFET<sup>®</sup> II MOSFET is Fairchild Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET II MOSFET easy-drive series offers slightly slower rise and fall times compared to the SuperFET II MOSFET series. Noted by the "E" part number suffix, this family helps manage EMI issues and allows for easier design implementation. For faster switching in applications where switching losses must be at an absolute minimum, please consider the SuperFET II MOSFET series.





#### Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Symbol		FCP125N60E	Unit		
V <sub>DSS</sub>	Drain to Source Voltage			600	V
V <sub>GSS</sub>	Gate to Source Voltage	- DC		±20	V
		- AC	(f > 1 Hz)	±30	- V
ID	Drain Current	- Continuous (T <sub>C</sub> = 25 <sup>o</sup> C)		29	A
		- Continuous (T <sub>C</sub> = 100 <sup>o</sup> C)		18	
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	87	А
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)			720	mJ
I <sub>AR</sub>	Avalanche Current (Note 1)			6	А
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)			2.78	mJ
dv/dt	MOSFET dv/dt			100	V/ns
	Peak Diode Recovery dv/dt (Note 3)			20	
P <sub>D</sub>	Devues Dissingtion	(T <sub>C</sub> = 25 <sup>o</sup> C)		278	W
	Power Dissipation	- Derate Above 25°C		2.2	W/ºC
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +150	°C
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			300	°C

#### **Thermal Characteristics**

Symbol	Parameter	FCP125N60E	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.45	°C/W
$R_{ hetaJA}$	Thermal Resistance, Junction to Ambient, Max.	40	°C/W

FCP125N60E

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N-Channel SuperFET<sup>®</sup> II Easy-Drive MOSFET

FCP125N60E         aracteristics         Tracteristics         Tracteristics         Tracteristics         to Source Breakdown V         adown Voltage Temperate         icient         Gate Voltage Drain Current         ics         Threshold Voltage         Drain to Source On Resard Transconductance         :teristics         Capacitance         it Capacitance	roltage ure ent t	Tube         Tube         otherwise noted.         Test Condition         V <sub>GS</sub> = 0 V, I <sub>D</sub> = 10 mA         V <sub>GS</sub> = 0 V, I <sub>D</sub> = 10 mA         I <sub>D</sub> = 10 mA, Reference         V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0         V <sub>DS</sub> = 480 V, V <sub>GS</sub> = 0         V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0         V <sub>GS</sub> = 10 V, I <sub>D</sub> = 250 $\mu$ V <sub>GS</sub> = 10 V, I <sub>D</sub> = 14.5 $\mu$ V <sub>DS</sub> = 20 V, I <sub>D</sub> = 14.5 $\mu$	, $T_J = 25^{\circ}C$ , $T_J = 150^{\circ}C$ ed to $25^{\circ}C$ V V, $T_C = 125^{\circ}C$ V A A	Min. 600 650 - - - 2.5 - -	N/A Typ. - 0.7 - 2 - 102	50 u Max. - - 1 ±100	Units Unit V V/ <sup>o</sup> C μΑ nA
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adown Voltage Temperati icient Gate Voltage Drain Current to Body Leakage Current <b>CS</b> Threshold Voltage Drain to Source On Res ard Transconductance <b>Ceristics</b> Capacitance	ent	$\begin{split} I_{D} &= 10 \text{ mA, Reference} \\ V_{DS} &= 600 \text{ V}, \text{ V}_{GS} = 0 \\ V_{DS} &= 480 \text{ V}, \text{ V}_{GS} = 0 \\ V_{GS} &= \pm 20 \text{ V}, \text{ V}_{DS} = 0 \\ \end{split}$	ed to $25^{\circ}$ C V V,T <sub>C</sub> = $125^{\circ}$ C V A A	- - -	0.7 - 2 - 102	1 - ±100 3.5	V/°C μA nA
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Drain to Source On Res ard Transconductance cteristics Capacitance	sistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 14.5	A	-	-	105	
cteristics Capacitance		00		-		125	mΩ
Capacitance					25	-	S
Capacitance							1
				-	2250	2990	pF
		$V_{\rm DS}$ = 380 V, $V_{\rm GS}$ = 0	V,	-	60	80	pF
rse Transfer Capacitance	e	f = 1 MHz	_	-	17	-	pF
	-	$V_{DS} = 0 V \text{ to } 480 V, V_{0}$		-	258	-	pF
				-	75	95	nC
		$V_{GS} = 10 V$		-	10	-	nC
			(Note 4)	-	33	-	nC
alent Series Resistance		f = 1 MHz		-	3.5	-	Ω
cteristics							
				-	23	56	ns
,		$V_{DD} = 380 \text{ V}, \text{ I}_{D} = 14.5 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{g} = 4.7 \Omega$ (Note 4)		-	20	50	ns
Off Delay Time				-	106	222	ns
				-	23	56	ns
ode Characteristic	e						1
		e Forward Current		-	-	29	A
imum Pulsed Drain to Source Diode Forward Current		-	-	87	Α		
				-	-	1.2	V
	-	000 000		-	376	-	ns
		dl <sub>F</sub> /dt = 100 A/µs		-	6.5	-	μC
	num Continuous Drain to num Pulsed Drain to Sou	Gate Charge at 10V to Source Gate Charge to Drain "Miller" Charge valent Series Resistance acteristics On Delay Time On Rise Time Off Delay Time Off Fall Time Off Fall Time ode Characteristics num Continuous Drain to Source Diode num Pulsed Drain to Source Diode Fo to Source Diode Forward Voltage rse Recovery Time	Gate Charge at 10V $V_{DS} = 380 \text{ V}, I_D = 14.5$ to Source Gate Charge $V_{GS} = 10 \text{ V}$ to Drain "Miller" Charge $V_{GS} = 10 \text{ V}$ valent Series Resistance $f = 1 \text{ MHz}$ acteristicsOn Delay Time $V_{DD} = 380 \text{ V}, I_D = 14.5$ Off Delay Time $V_{DD} = 380 \text{ V}, I_D = 14.5$ Off Fall Time $V_{GS} = 10 \text{ V}, R_g = 4.7 \text{ g}$ ode Characteristicsnum Continuous Drain to Source Diode Forward Currentnum Pulsed Drain to Source Diode Forward Currentto Source Diode Forward Voltage $V_{GS} = 0 \text{ V}, I_{SD} = 14.5 \text{ J}$ rse Recovery Time $V_{GS} = 0 \text{ V}, I_{SD} = 14.5 \text{ J}$	Gate Charge at 10V $V_{DS} = 380 \text{ V}, \text{ I}_{D} = 14.5 \text{ A},$ $V_{GS} = 10 \text{ V}$ to Source Gate Charge $V_{GS} = 10 \text{ V}$ to Drain "Miller" Charge $(\text{Note 4})$ valent Series Resistance $f = 1 \text{ MHz}$ acteristicsOn Delay Time $V_{DD} = 380 \text{ V}, \text{ I}_{D} = 14.5 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{g} = 4.7 \Omega$ Off Delay Time $V_{DD} = 380 \text{ V}, \text{ I}_{D} = 14.5 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{g} = 4.7 \Omega$ Off Fall Time $(\text{Note 4})$ ode Characteristicsnum Continuous Drain to Source Diode Forward Current num Pulsed Drain to Source Diode Forward Current to Source Diode Forward Voltage $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 14.5 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 14.5 \text{ A},$	Gate Charge at 10V to Source Gate Charge to Drain "Miller" Charge valent Series Resistance $V_{DS} = 380 \text{ V}, I_D = 14.5 \text{ A}, V_{GS} = 10 \text{ V}$ -Acteristics On Delay Time On Rise Time Off Delay Time Off Fall Time $V_{DD} = 380 \text{ V}, I_D = 14.5 \text{ A}, V_{GS} = 10 \text{ V}, R_g = 4.7 \Omega$ -Ode Characteristics num Continuous Drain to Source Diode Forward Current to Source Diode Forward Current-Ode Characteristics num Pulsed Drain to Source Diode Forward Current to Source Diode Forward Voltage-V_{GS} = 0 V, I_{SD} = 14.5 \text{ A}, V_{GS} = 0 V, I_{SD} = 14.5 \text{ A},The Recovery TimeV_{GS} = 0 V, I_{SD} = 14.5 \text{ A},V_{GS} = 0 V, I_{SD} = 14.5 \text{ A},The Recovery TimeV_{GS} = 0 V, I_{SD} = 14.5 \text{ A},	Gate Charge at 10V to Source Gate Charge $V_{DS} = 380 \text{ V}, \text{ I}_D = 14.5 \text{ A},$ $V_{GS} = 10 \text{ V}$ -75to Source Gate Charge to Drain "Miller" Charge $V_{GS} = 10 \text{ V}$ (Note 4)-33valent Series Resistancef = 1 MHz-3.5acteristicsOn Delay Time Off Delay Time $V_{DD} = 380 \text{ V}, \text{ I}_D = 14.5 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_g = 4.7 \Omega$ -23Off Delay Time Off Fall Time-23ode Characteristicsnum Continuous Drain to Source Diode Forward Current num Pulsed Drain to Source Diode Forward Currentnum Continuous Drain to Source Diode Forward Current $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 14.5 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 14.5 \text{ A},$ res Recovery Time $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 14.5 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 14.5 \text{ A},$ -376	Gate Charge at 10V $V_{DS} = 380 \text{ V}, I_D = 14.5 \text{ A},$ -       75       95         to Source Gate Charge $V_{GS} = 10 \text{ V}$ -       10       -         to Drain "Miller" Charge       (Note 4)       -       33       -         valent Series Resistance       f = 1 MHz       -       3.5       -         acteristics         On Delay Time $V_{DD} = 380 \text{ V}, I_D = 14.5 \text{ A},$ -       23       56         On Rise Time $V_{DS} = 10 \text{ V}, R_g = 4.7 \Omega$ -       106       222         Off Delay Time $V_{GS} = 10 \text{ V}, R_g = 4.7 \Omega$ -       106       222         Off Fall Time       (Note 4)       -       23       56         ode Characteristics         num Continuous Drain to Source Diode Forward Current       -       -       29         num Pulsed Drain to Source Diode Forward Current       -       -       87         to Source Diode Forward Voltage $V_{GS} = 0 \text{ V}, I_{SD} = 14.5 \text{ A},$ -       -       1.2         rse Recovery Time $V_{GS} = 0 \text{ V}, I_{SD} = 14.5 \text{ A},$ -       376       -

4. Essentially independent of operating temperature.

6

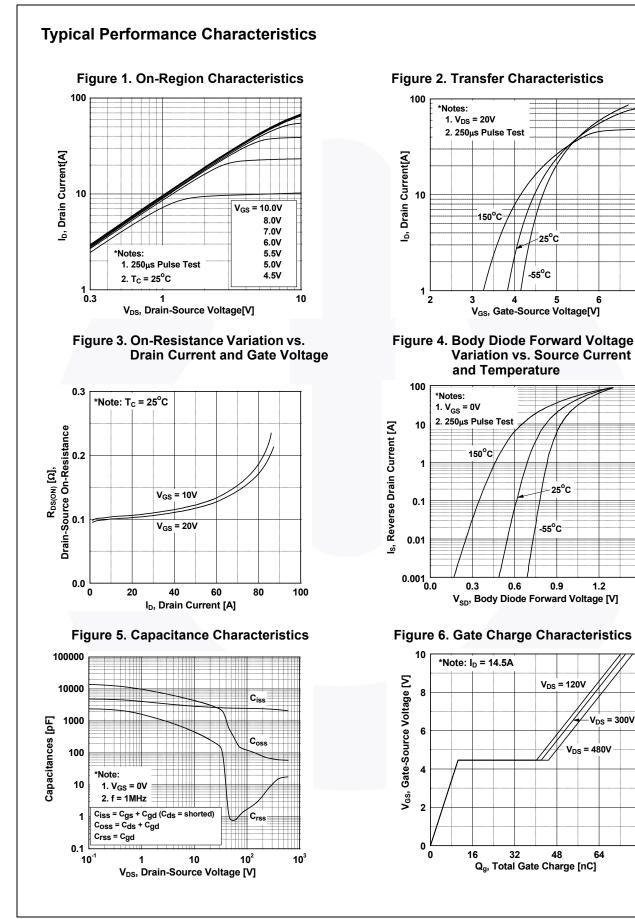
1.2

V<sub>DS</sub> = 300V

64

1.5

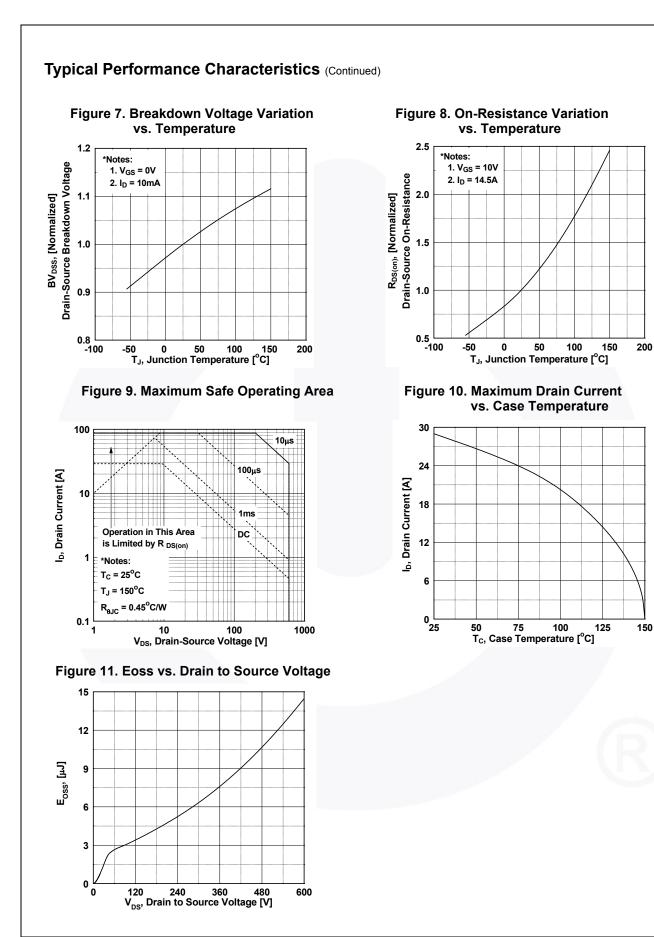
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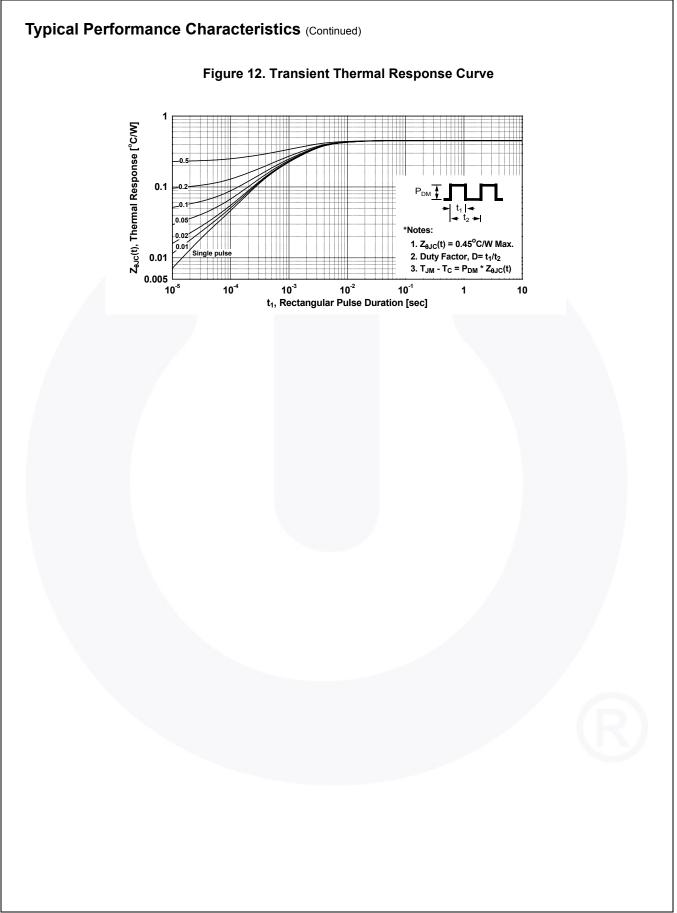
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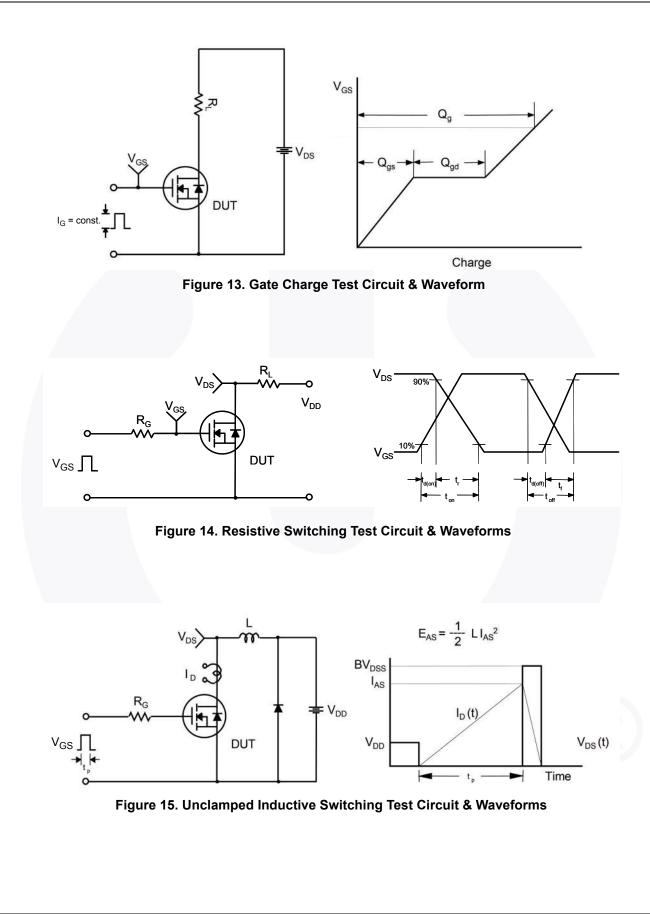
FCP125N60E — N-Channel SuperFET<sup>®</sup> II Easy-Drive MOSFET



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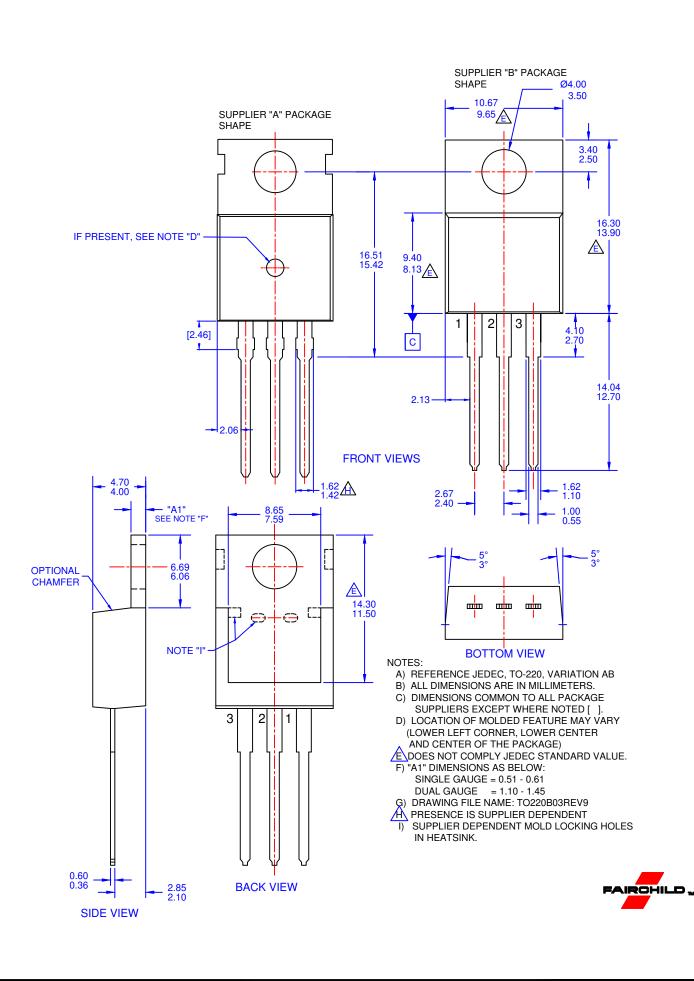
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FCP125N60E — N-Channel SuperFET<sup>®</sup> II Easy-Drive MOSFET

DUT + ۱<sub>sd</sub> م 0 L Driver R<sub>G</sub> Same Type as DUT  $V_{DD}$ ∏∏ v<sub>gs</sub> - dv/dt controlled by  $R_{G}$ -  $\mathbf{I}_{\mathrm{SD}}$  controlled by pulse period Î Gate Pulse Width  $V_{GS}$ D = Gate Pulse Period 10V (Driver) T I<sub>FM</sub> , Body Diode Forward Current  $I_{SD}$ di/dt (DUT)  $I_{RM}$ Body Diode Reverse Current  $V_{\text{DS}}$ (DUT) Body Diode Recovery dv/dt V<sub>SD</sub> V<sub>DD</sub> Body Diode Forward Voltage Drop Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms



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